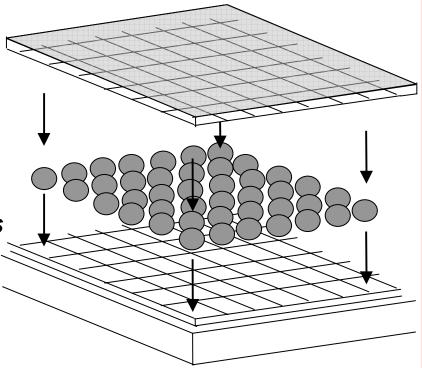
Integrating Pixel Array Detectors

Sol Gruner Dept. of Physics & CHESS Cornell University

Detector development groupMark TateAlper ErcanFormer rDan SchuetteSandor EDarol ChamberlainBob WixtLucas KoernerEric EikeHugh PhillipGuiseppe

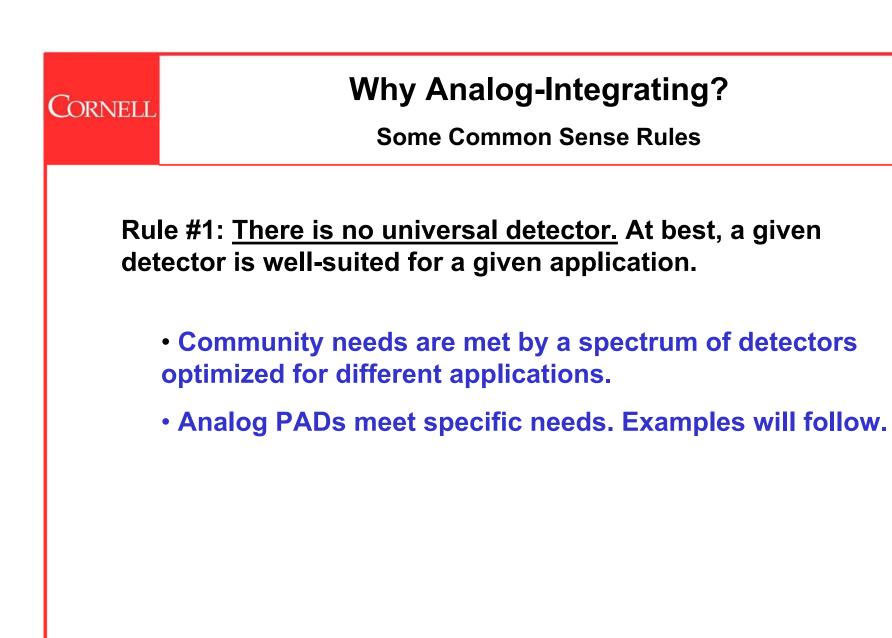
Former members Sandor Barna Bob Wixted Eric Eikenberry Guiseppe Rossi Matt Renzi



Basic Pixel Array Detector (PAD)

Diode Detection Layer

X-rays • Fully depleted, high resistivity Direct x-ray conversion • Silicon, GaAs, CdTe, etc. **Connecting Bumps** Solder or indium • 1 per pixel **CMOS** Layer Signal processing Signal storage & output Gives enormous flexibility!



Why Analog-Integrating?

Some Common Sense Rules

Rule #2: The <u>accuracy</u> of a given measurement is not necessarily better or worse just because a photon-counting or an analog-integrating detector is used.

Accuracy depends on many real-world details of both the experiment and the detector, including:

- Calibrations
- Stability

 Photon loss due to, e.g., pixel signal-sharing, charge recombination, count-rate limitations, and x-ray absorption by inert structures

Systematic effects, e.g., cross-talk, pickup noise

Analog-integrators have successfully demonstrated excellent performance to appropriate accuracy in certain experiments.

Why Analog-Integrating?

Some Common Sense Rules

Rule #3: <u>Any detector is only as good as its calibration</u>. In practice area detectors rarely achieve accuracies of 1%, and never better than a few tenths percent.

This is especially true for:

- Signals whose width is smaller than a pixel
- Very high local count-rates

For certain applications, analog-integrators have been very successfully calibrated.

Why Analog-Integrating?

Some Common Sense Rules

Rule #4: No matter how good you think a detector is, <u>you are</u> <u>bound to be in for nasty surprises</u> when you actually perform stringent performance tests.

Be skeptical of detector claims that are not backed up by appropriate, independently-repeated test data.

Analog-integrators have been around long enough that many of the nasty surprises are understood.

- Very high local count-rates. Examples:
 - ✓ Time-resolved radiography (e.g., >10¹⁰ x-ray/pix/sec)
 - ✓ Many XFEL & ERL applications (e.g., x-rays in femtoseconds)
 - ✓ Very low contrast imaging against high local backgrounds

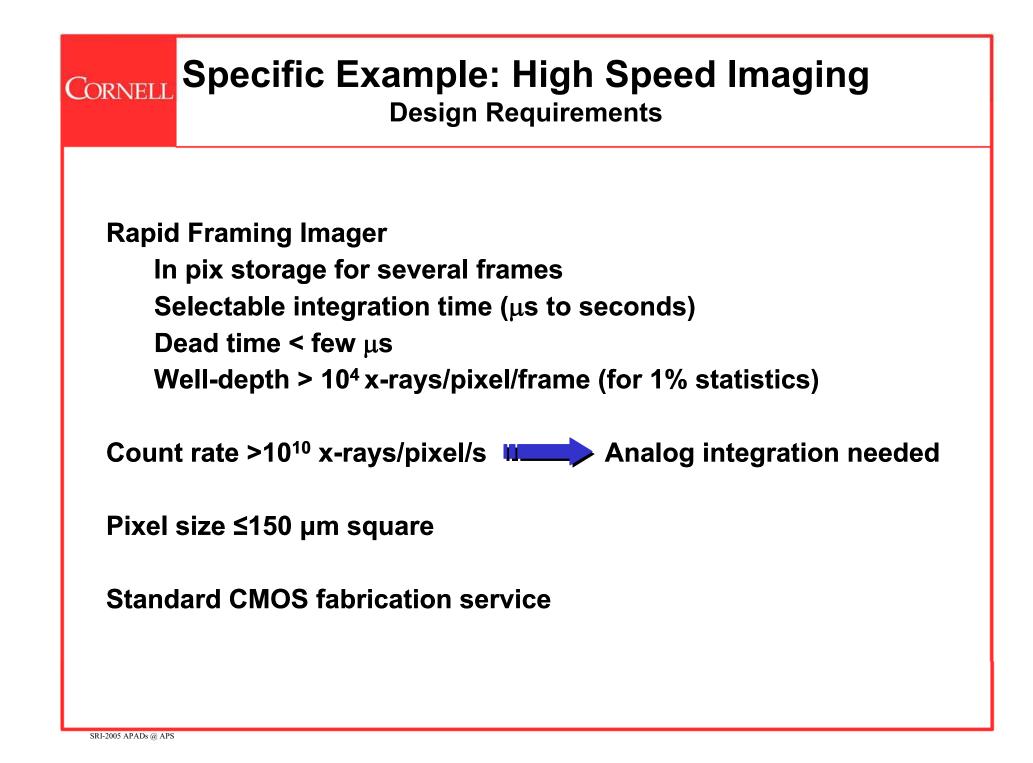
Analog-Integrating PADs are especially useful for...

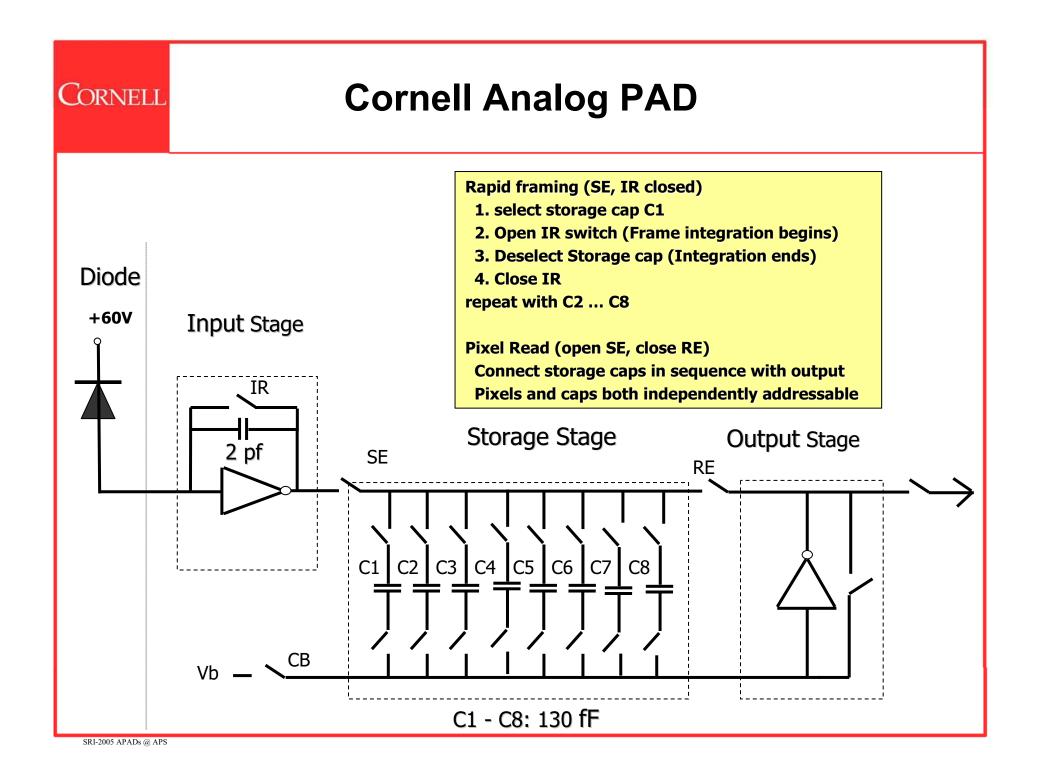
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- Accurate measurements of small-sized signals. Examples:
 - ✓ Microcrystallography from low mosaic spread crystals.
 - ✓ Micro-radiography and tomography
 - ✓ Accurate difference imaging of spatially fine features.

Analog-Integrating PADs are especially useful for...

- Very high local count-rates. Examples:
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- Accurate measurements of small-sized signals. Examples:
 - ✓ Microcrystallography from low mosaic spread crystals.
 - ✓ Micro-radiography and tomography
 - ✓ Accurate difference imaging for images with fine features.
- Problems involving complex analog signal processing. Example:

✓ In-pixel time-correlation of images (e.g., high count-rate speckle experiments).

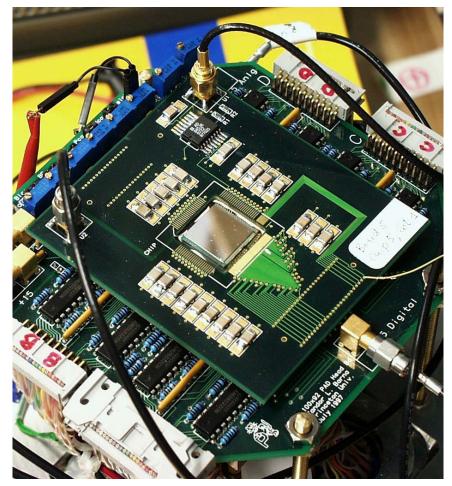




Cornell 100x92 Analog PAD

1.2 mm HP CMOS process (MOSIS) (Linearized Capacitors)
15 x 13.8 mm² active area; 100x92 pixels
150 mm square pixel
300 mm thick, high resistivity Si diode wafer (SINTEF)
120 mm solder bump bond (GEC-Marconi)

100x92 PAD developers include: Sandor Barna Eric Eikenberry Alper Ercan Sol Gruner Matt Renzi Giuseppe Rossi Mark Tate Bob Wixted



G. Rossi, et al, J Synchrotron Rad. (1999). 6, 1095-1105.

100 x 92 Prototype Tests

Test results with 8.9 keV x-rays

•	Full well capacity (x-rays)	17000
٠	Non-linearity (% full well)	< 0.5 %
٠	RMS read noise : (x-rays/pixel)	2.0 – 2.8
•	Dark current (-20 C) (x-ray/pixel/s) (fA/pixel)	1.6 – 7.7 6 – 40
•	Storage capacitor leakage	0.07% / s
٠	PSF (@75μm)	< 1%
٠	X-rays stopped in diode	97 %
•	Minimum integration period (μs)	0.15
•	Minimum deadtime between frames (μs)	0.6
•	Rad damage threshold (kRad, CMOS oxide)	30
•	Tolerable radiation dose (kRad)	>300

High speed radiography: Supersonic spray from diesel fuel injector

X-ray beam

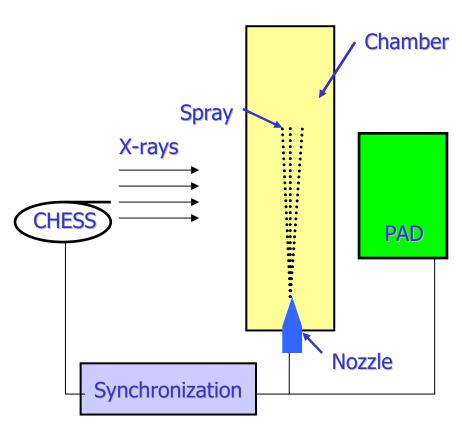
- ČHESS Beamline D-1
- 6 keV (1% bandpass)
- 2.5 mm x 13.5 mm (step sample to tile large area)
- 10⁸ 10⁹ x-rays/pix/s
- 5.13 μs integration (2x ring period)

Diesel Fuel Injection System

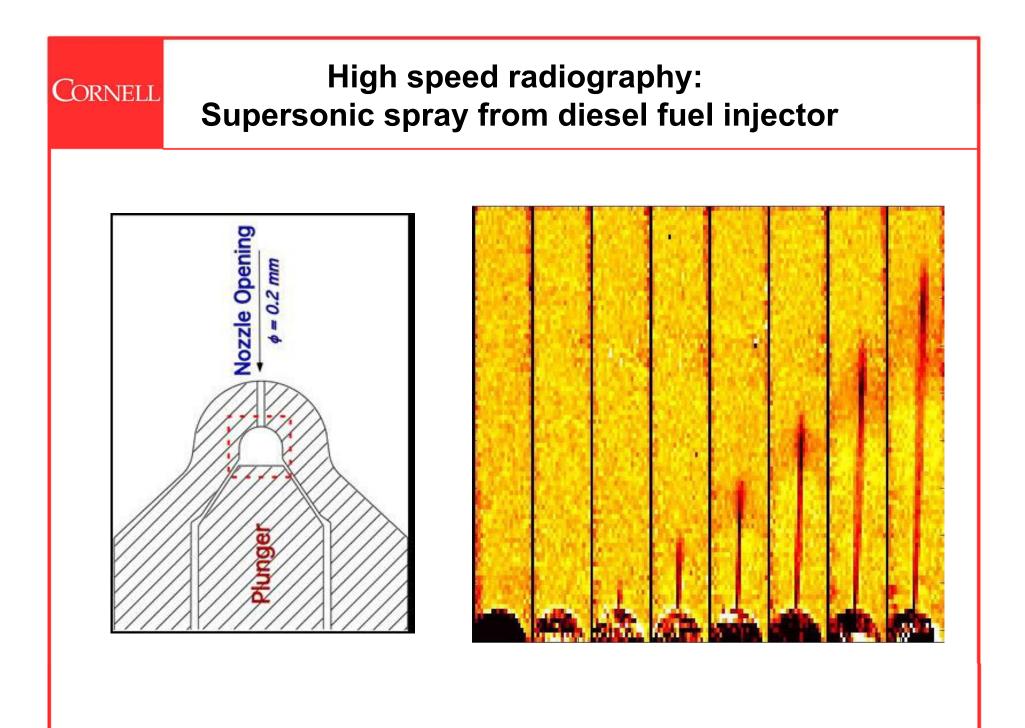
- Cerium added for x-ray contrast
- 1350 PSI gas driven
- 1.1 ms pulse
- 1 ATM SF₆ in chamber

Collaboration: Jin Wang (APS) & S.M. Gruner (Cornell)

See: McPhee, Tate, Powell, Yue, Renzi, Ercan, Narayanan, Fontes, Walther, Schaller, Gruner & Wang Science 295 (2002) 1261-1263.



SRI-2005 APADs @ APS

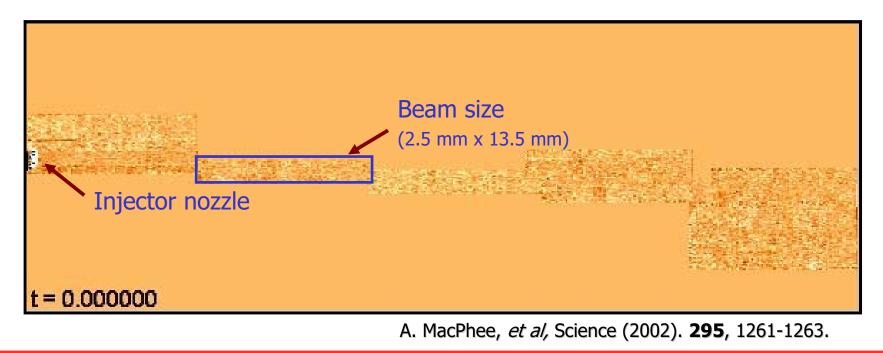


SRI-2005 APADs @ APS



Diesel fuel injector spray

- 1.3 ms time sequence (composite of 34 sample positions)
- 5.13 μ s exposure time (2.56 μ s between frames)
- 168 frames in time (21 groups of 8 frames) Average 20x for S/N
- Sequence comprised of 5 x 10⁴ images



Gasoline fuel injector spray

X-ray beam

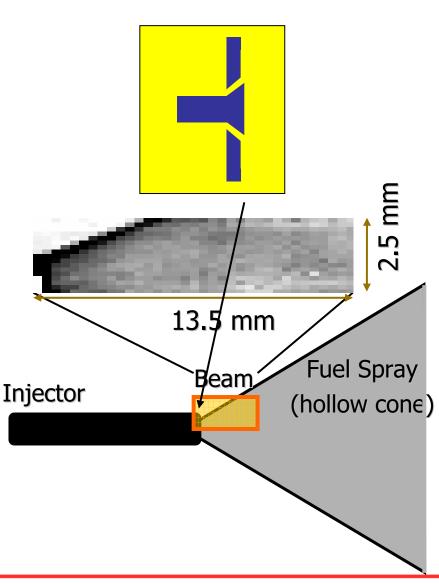
- CHESS Beamline D-1
- 6 keV (1% bandpass)
- 2.5 mm x 13.5 mm
- (step sample to tile large area)
- 10⁹ x-rays/pix/s
- 5.13 μs integration (2x ring period)

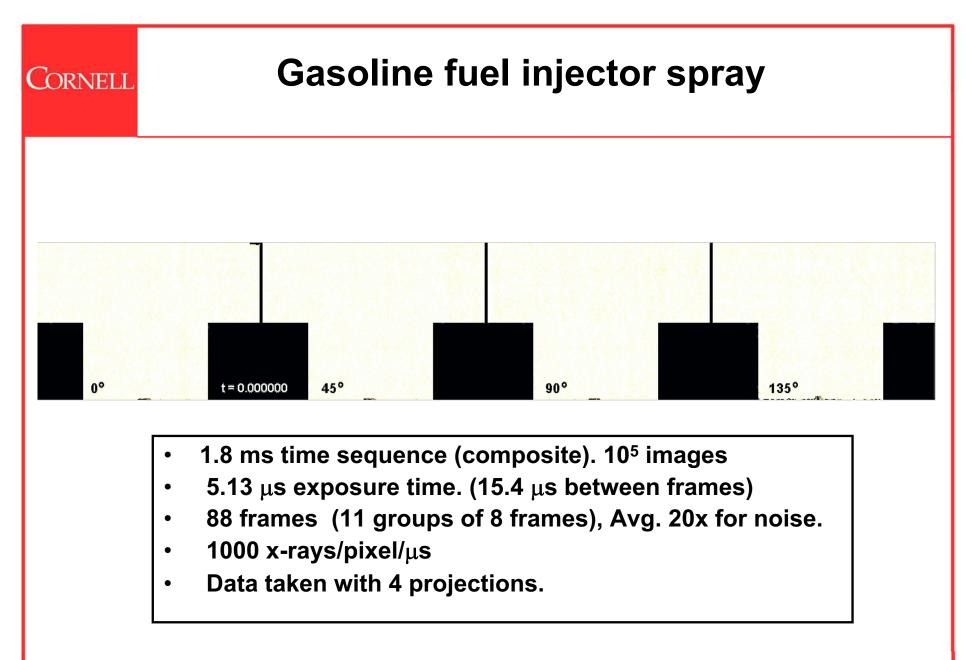
Fuel injection system

- Cerium added for x-ray contrast
- 1000 PSI gas driven
- 1 ms pulse
- 1 ATM Nitrogen

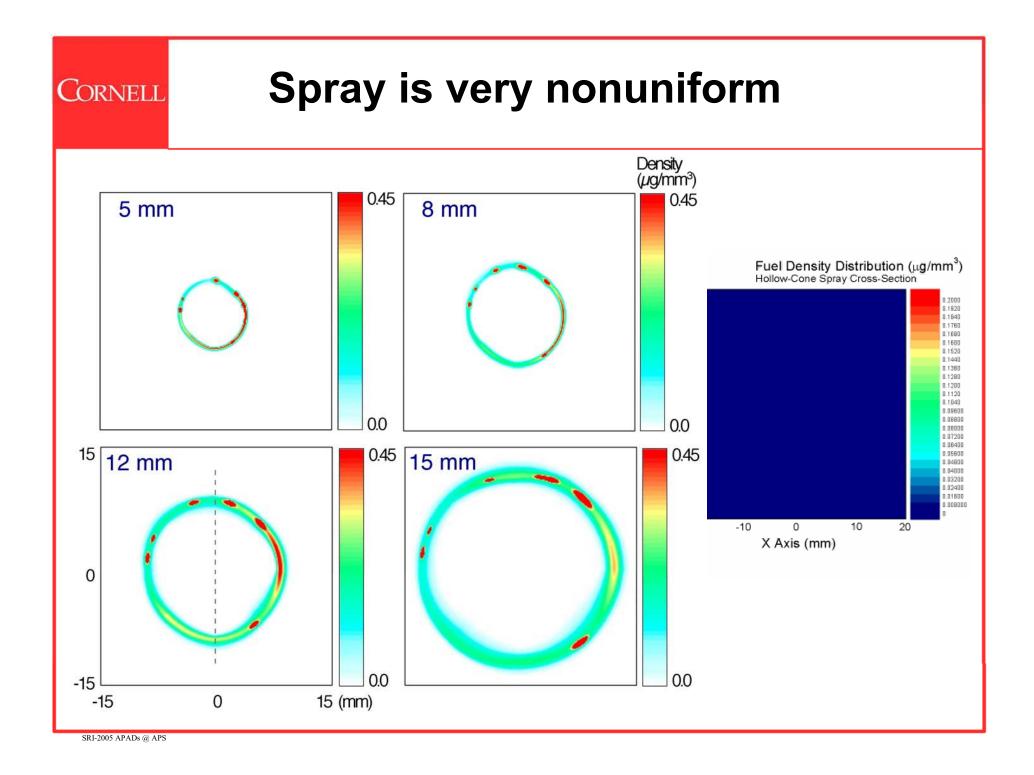
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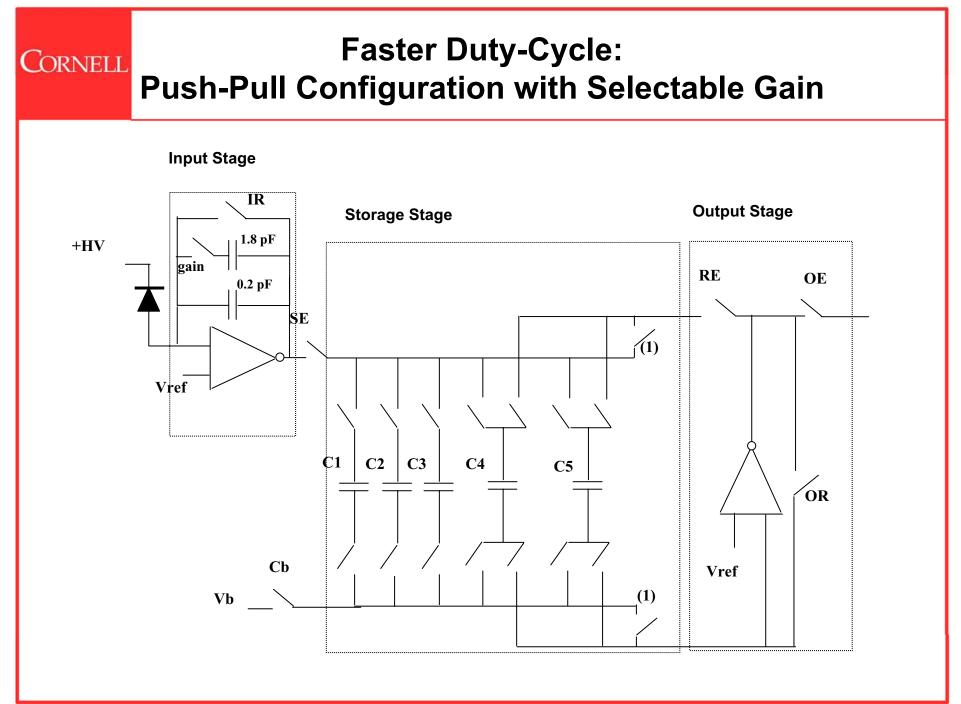
See: Cai, Powell, Yue, Narayanan, Wang, Tate, Renzi, Ercan, Fontes & Gruner Appl. Phys. Lett. <u>83</u> (2003) 1671.

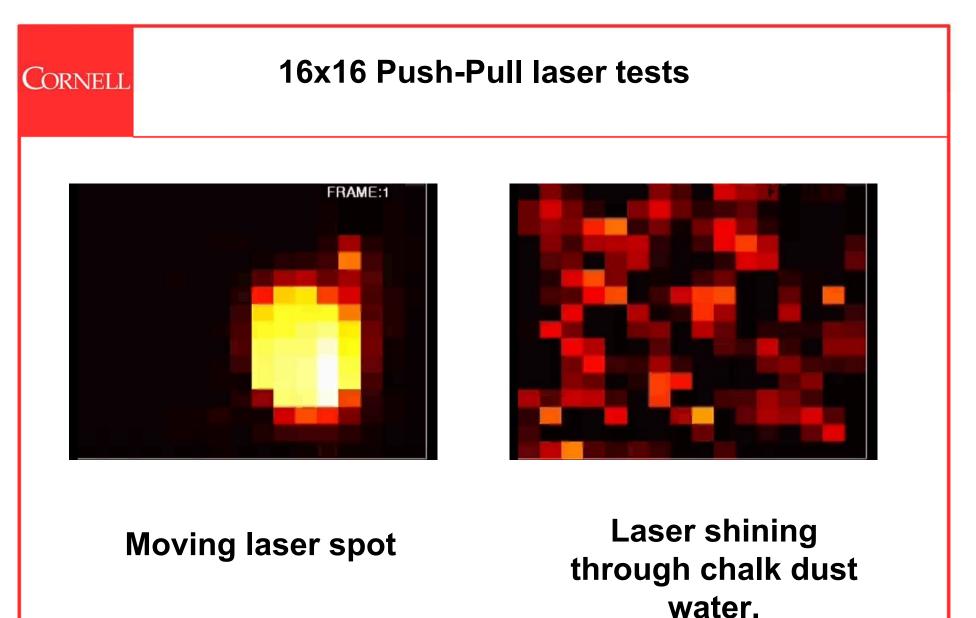




See poster for more experiments







PAD design: Matt Renzi, Alper Ercan

Tests: Alper Ercan

120 frames/sec

• Calibration issues limit accuracy to few tenths percent, e.g., 1 part in 1,000 exceeds state-of-art.

 Range of numbers in an image (e.g., SAXS) may span many orders of magnitude.

Suggests that users really want to record images that span many orders of magnitude of intensity across the image, but only need few tenths % accuracy at any location.

Mixed Mode Pixel

Crystallography detector:

Goals:

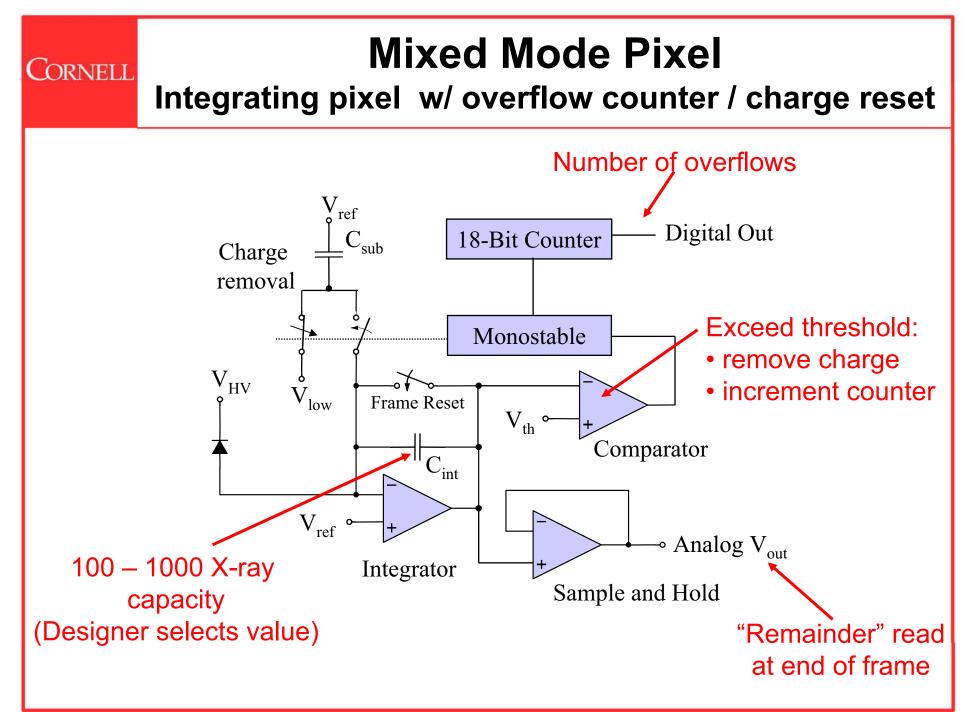
- Increase dynamic range (10⁷ x-rays)
- Keep high count rates (>10⁸ Hz)
- Fast framing (< 1ms dead time)
- 2k x 2k pixels, 150 μ m pixel size

Methods:

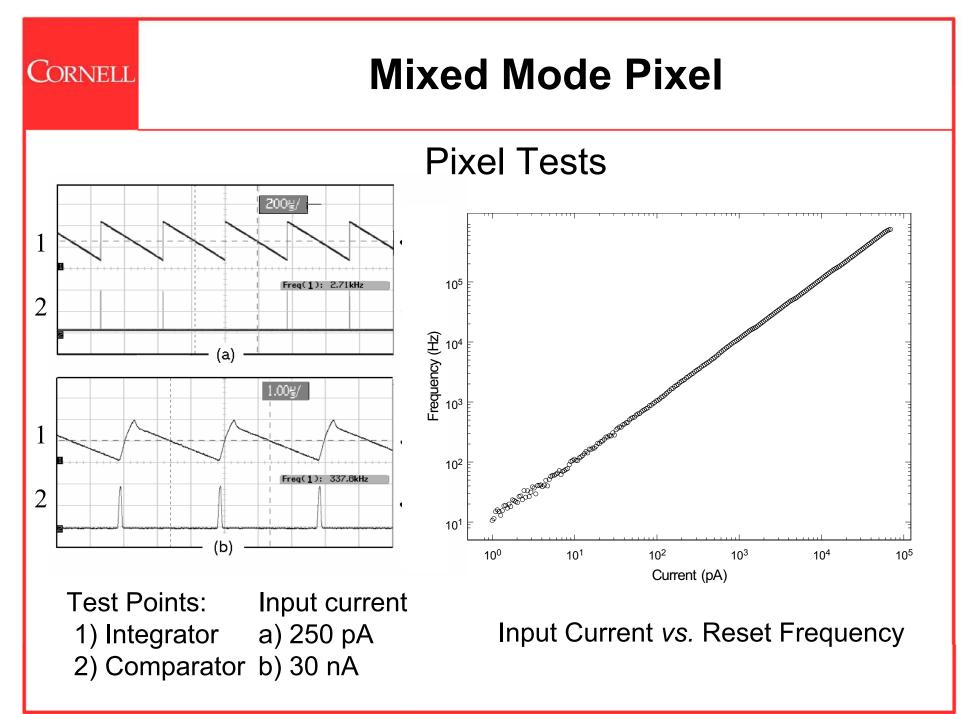
- Integrating pixel w/ digital overflow counter / charge reset
- Analog remainder read at end of frame
- Fabricated in 0.25 μ m TSMC 3.3 V, metal on metal capacitors

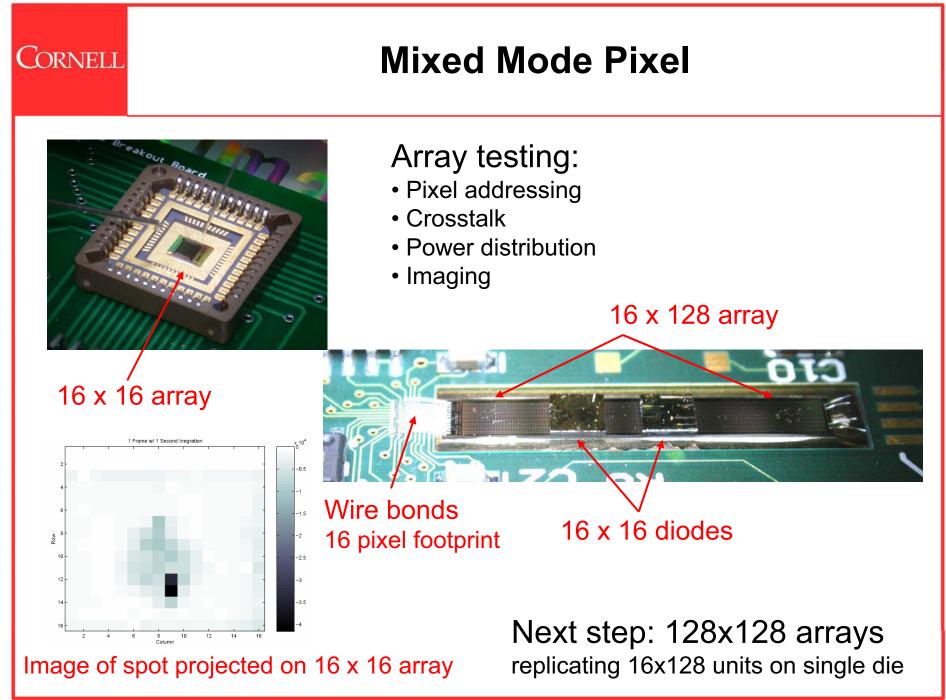
Collaboration with ADSC. See

S.G. Angello, et al, IEEE 2004 Nuc. Sci. Symposium, Rome, (Oct. 16-22, 2004).



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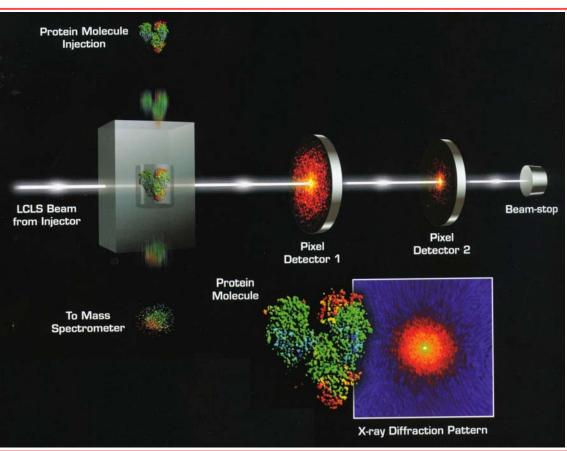


SRI-2005 APADs @ APS

Integrating PAD for LCLS Single Particle Imaging

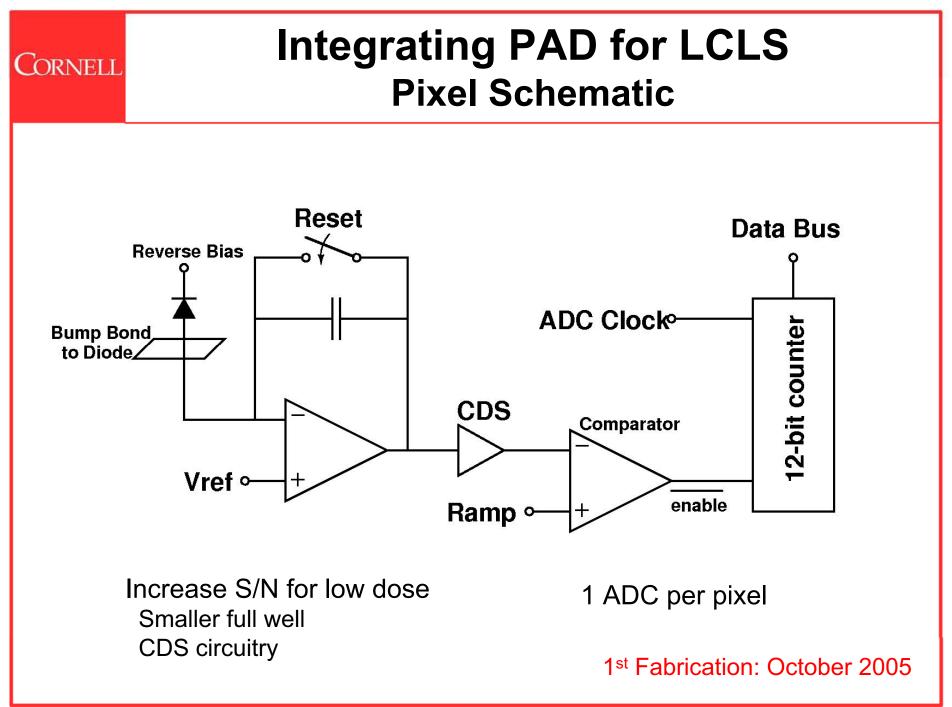
Imaging requirements

- Large solid angle coverage
- <230 fs pulses. Perhaps 2fs.</p>
- 120 Hz framing
- 10¹² x-rays/pulse
- 0 1000 x-rays / pixel
 Distinguish between
 0 and 1 x-ray



Pixel detector 1: Wide angle

S/N per x-ray >> 1 Dynamic range ~ 10³ > 512 x 512 pixels Pixel detector 2: Small angle S/N per x-ray ~1 Dynamic range ~ 10³ - 10⁴ > 512 x 512 pixels



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